



# SMTV06N028SL3H

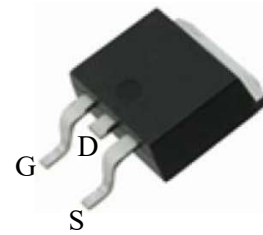
## N-Channel Enhancement Mode Field Effect Transistor

### FEATURES

- Advanced trench cell design
- High speed switch
- Suffix "H" indicates Halogen-free parts, ex.SMTV06N028SL3H

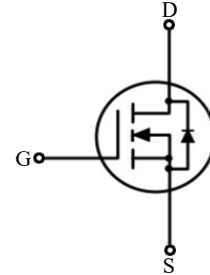
### PIN CONFIGURATION

TO-263



TOP VIEW

D	Drain
G	Gate
S	Source



### Maximum Ratings ( $T_A=25\text{ }^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit	
Drain-Source Voltage	$V_{DS}$	60	V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$		
Continuous Drain Current	$I_D$	$T_C=25\text{ }^\circ\text{C}$	120	A
		$T_C=100\text{ }^\circ\text{C}$	77	
Pulsed Drain Current (Note 1)	$I_{DM}$	480	A	
Avalanche Current	$I_{AS}$	44.8	A	
Single Pulse Avalanche Energy (Note 2)	$E_{AS}$	100.3	mJ	
Power Dissipation	$P_D$	62.5	W	
Thermal Resistance from Junction to Ambient (Note 3)	$R_{\theta JA}$	40	$^\circ\text{C}/\text{W}$	
Thermal Resistance from Junction to Case	$R_{\theta JC}$	2	$^\circ\text{C}/\text{W}$	
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	- 55 to + 150	$^\circ\text{C}$	

Note:

1. The data tested by pulsed, pulse width  $\leq 100\mu\text{s}$ , duty cycle  $\leq 2\%$ , Reptitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150\text{ }^\circ\text{C}$ .
2. Limited by  $T_{J(MAX)}$ , starting  $T_J=25\text{ }^\circ\text{C}$ ,  $L=0.1\text{mH}$ ,  $R_g=25\Omega$ ,  $I_{AS}=44.8\text{A}$ ,  $V_{GS}=10\text{V}$ .
3. Device mounted on FR-4 substrate PC board, 2oz copper, with 1 inch<sup>2</sup> copper plate in still air.



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### Electrical Characteristics ( $T_A = 25\text{ }^\circ\text{C}$ unless otherwise specified)

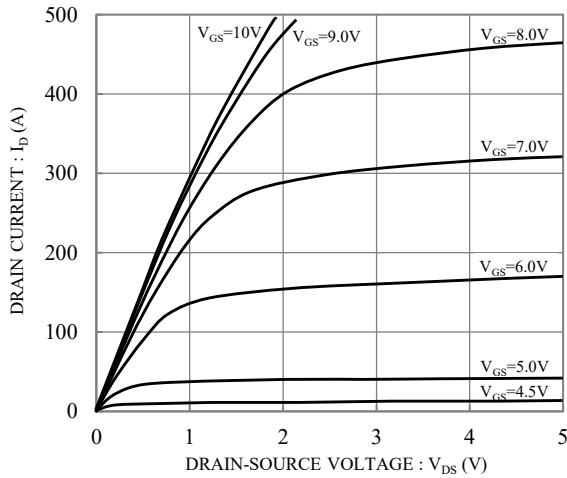
Parameter	Conditions	Symbol	Min.	Typ.	Max.	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$I_D = 1\text{mA}$	$V_{(BR)DSS}$	60	-	-	V
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 120\mu\text{A}$	$V_{GS(th)}$	2.0	-	4.0	V
Zero Gate Voltage Drain Current	$V_{DS} = 60\text{V}$	$I_{DSS}$	-	-	1	$\mu\text{A}$
Gate Leakage Current	$V_{GS} = \pm 20\text{V}$	$I_{GSS}$	-	-	$\pm 100$	nA
Drain-Source On-Resistance	$V_{GS} = 10\text{V}, I_D = 100\text{A}$	$R_{DS(on)}$	-	2.8	3.2	m $\Omega$
<b>Dynamic</b>						
Gate Resistance	$V_{DS} = 0\text{V}, V_{GS} = 0, f = 1\text{MHz}$	$R_g$	-	1.1	-	$\Omega$
Total Gate Charge	$V_{DS} = 30\text{V}, V_{GS} = 10\text{V}, I_D = 25\text{A}$	$Q_g$	-	75	-	nC
Gate-Source Charge		$Q_{gs}$	-	23	-	
Gate-Drain Charge		$Q_{gd}$	-	22	-	
Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$	$C_{iss}$	-	4597	-	pF
Output Capacitance		$C_{oss}$	-	2133	-	
Reverse Transfer Capacitance		$C_{rss}$	-	110	-	
Turn on Delay Time	$V_{DS} = 30\text{V}, I_D = 25\text{A}, V_{GS} = 10\text{V}, R_g = 4.7\Omega, R_L = 1.2\Omega$	$t_{d(on)}$	-	39	-	ns
Turn on Rise Time		$t_r$	-	69	-	
Turn off Delay Time		$t_{d(off)}$	-	27	-	
Turn off Fall Time		$t_f$	-	9	-	
<b>Drain-Source Body Diode</b>						
Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 100\text{A}$	$V_{SD}$	-	-	1.3	V
Diode Continuous Forward Current	-	$I_S$	-	-	120	A
Diode Pulse Current		$I_{SM}$	-	-	480	A
Reverse Recovery Time	$I_S = 25\text{A}, di/dt = 100\text{A}/\mu\text{s}$	$t_{rr}$	-	44	-	ns
Reverse Recovery Charge		$Q_{rr}$	-	40	-	nC



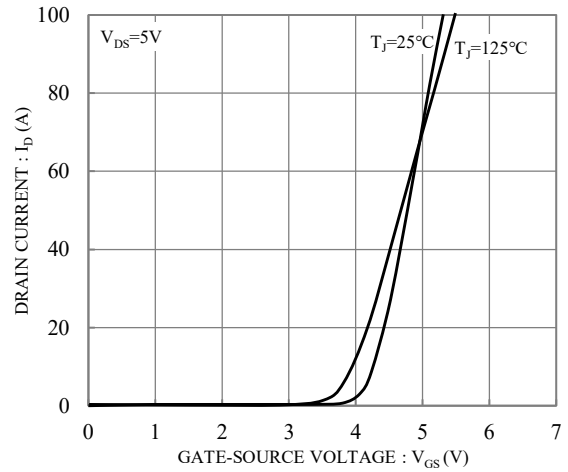
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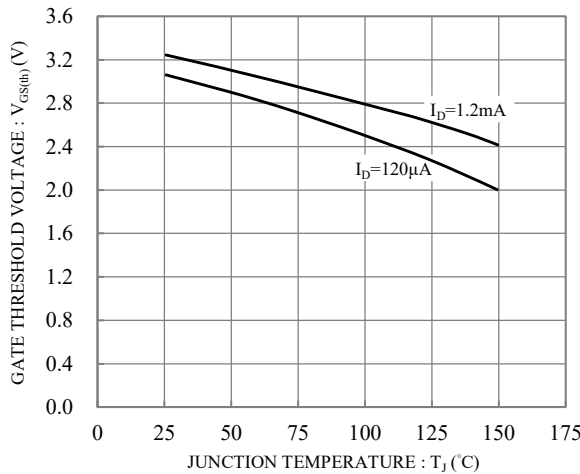
### RATINGS AND CHARACTERISTIC CURVES



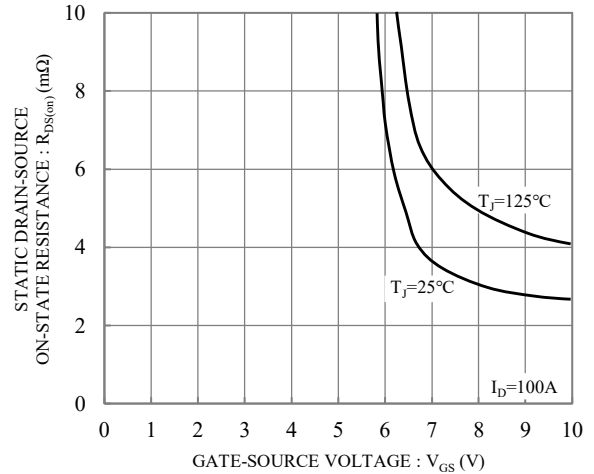
**Fig.1 Typical Output Characteristics**



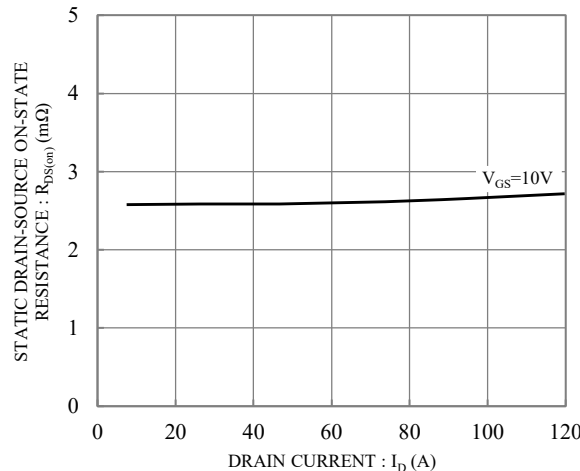
**Fig.2 Typical Transfer Characteristics**



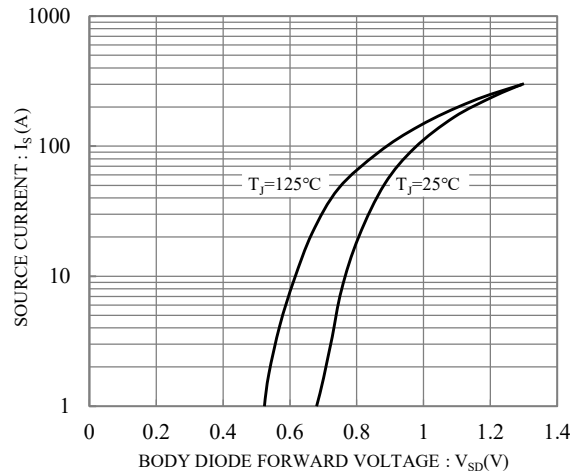
**Fig.3 Gate Threshold Voltage vs. Junction Temperature**



**Fig.4 Static Drain-Source On-State Resistance vs. Gate-Source Voltage**



**Fig.5 Static Drain-Source On-State Resistance vs. Drain Current**

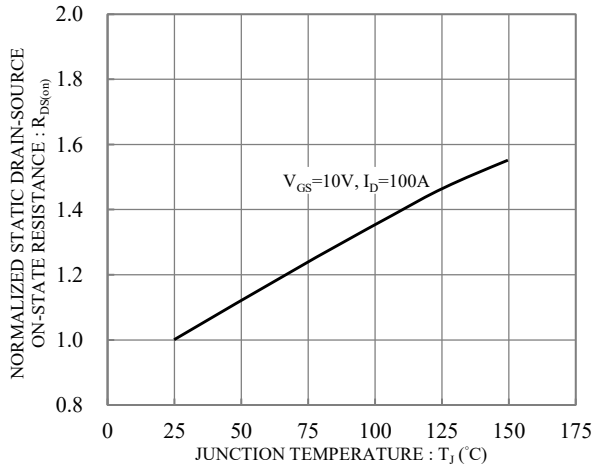


**Fig.6 Body Diode Forward Voltage vs. Source Current**

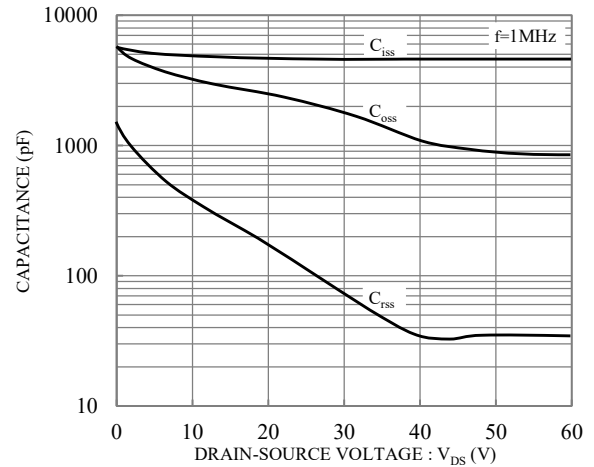


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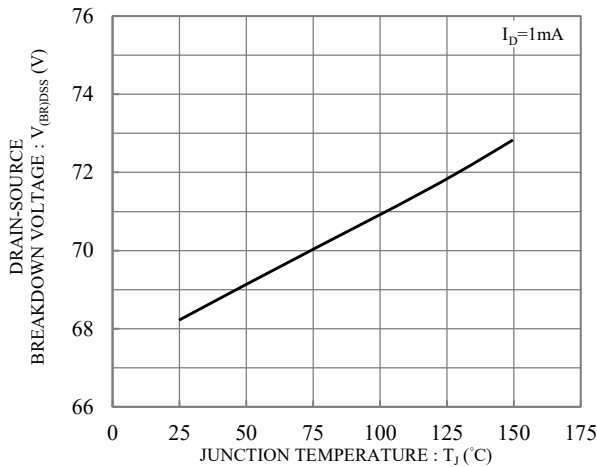
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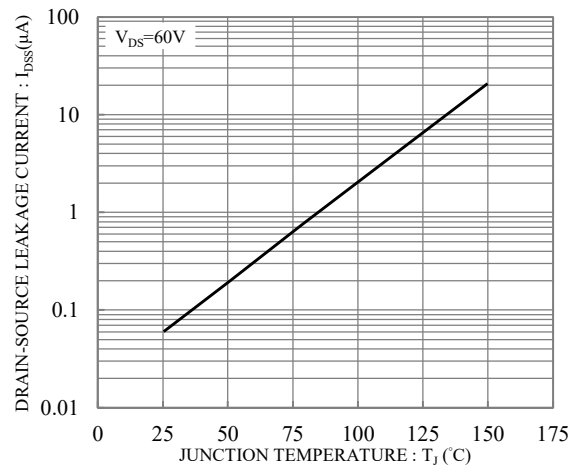
**Fig.7 Drain-Source On-State Resistance vs Junction Temperature**



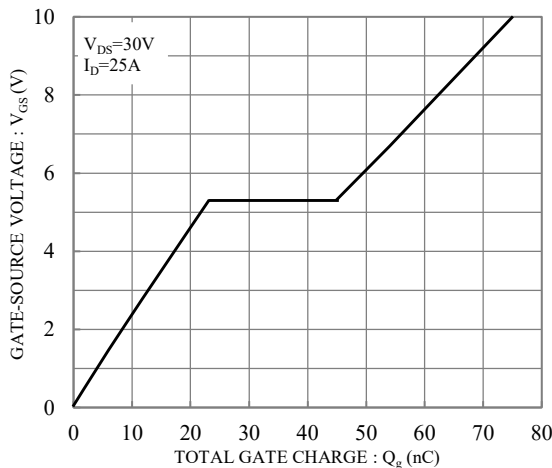
**Fig.8 Capacitance vs Drain-Source Voltage**



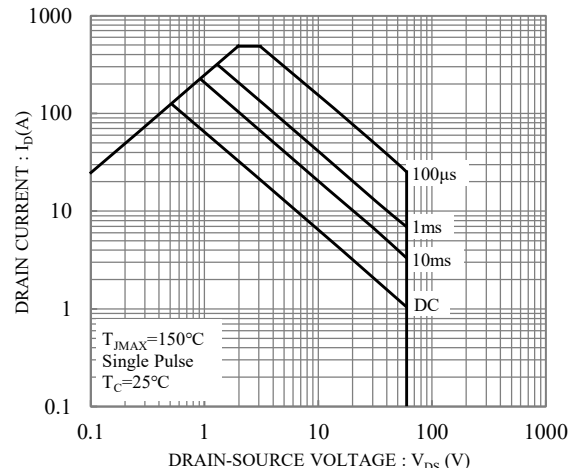
**Fig.9 Breakdown Voltage vs Junction Temperature**



**Fig.10 Drain-Source Leakage Current vs Junction Temperature**



**Fig.11 Gate Charge Characteristics**

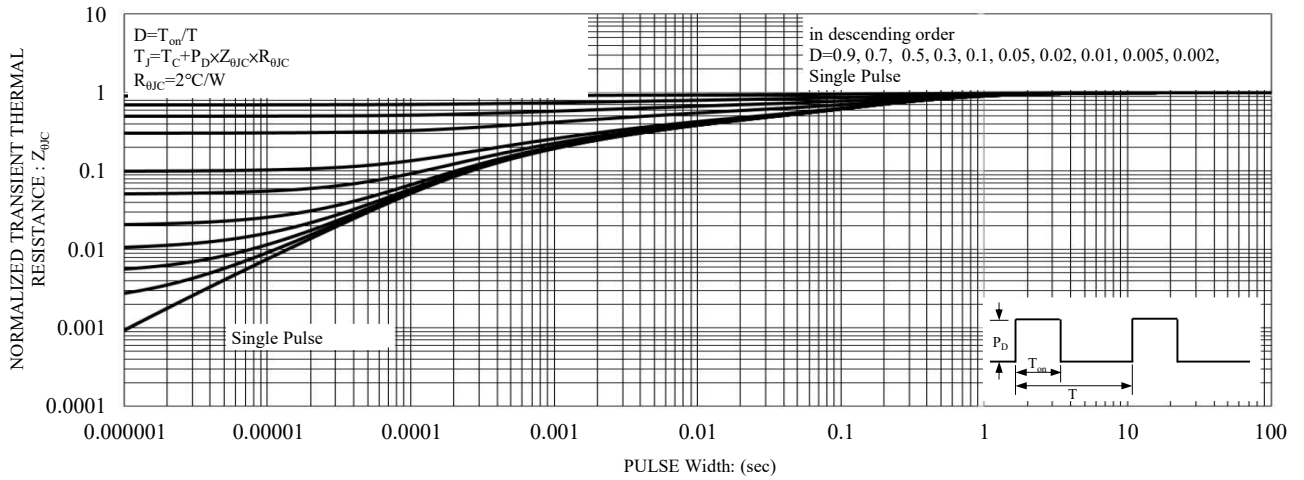


**Fig.12 Drain-Source Leakage Current vs Junction Temperature**

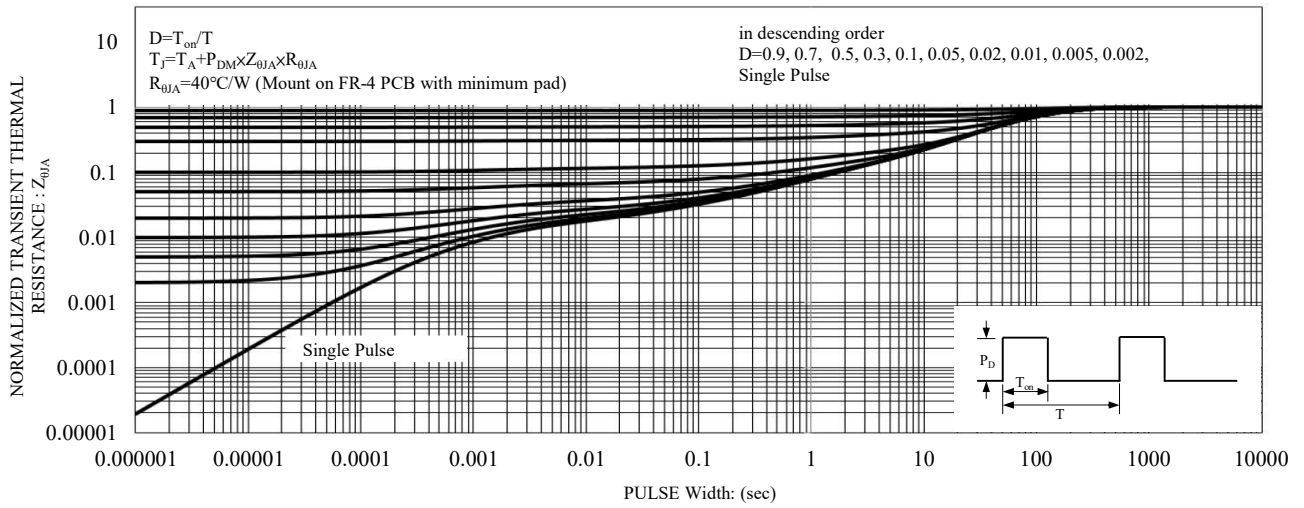


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**Fig.13 Maximum Transient Thermal Impedance**



**Fig.14 Maximum Transient Thermal Impedance**

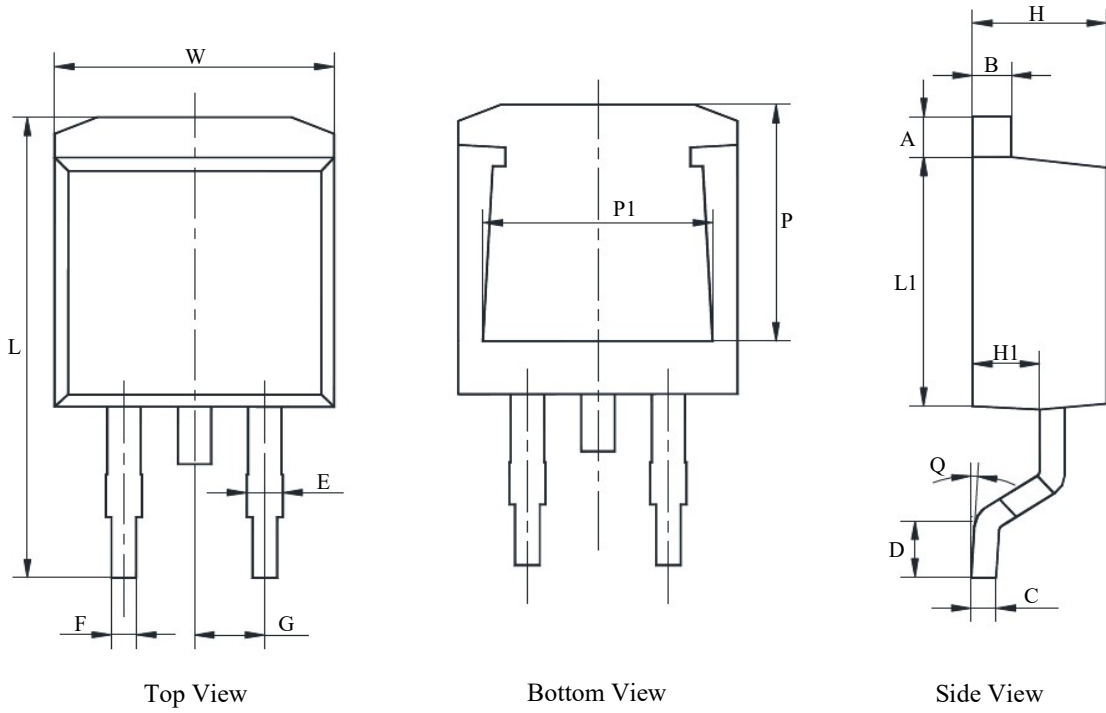


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### PACKAGE DIMENSION

### TO-263



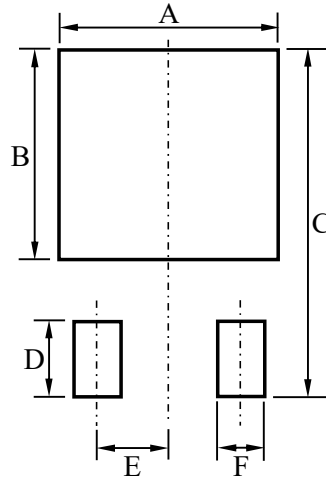
Symbol	Millimeters		Inches	
	Min	Max	Min	Max
A	1.10	1.50	0.043	0.059
B	1.10	1.50	0.043	0.059
C	0.30	0.50	0.012	0.020
D	2.15	2.60	0.085	0.102
E	1.10	1.60	0.043	0.063
F	0.68	0.94	0.027	0.037
G	Typ. 2.54		Typ. 0.100	
W	9.60	10.50	0.378	0.413
H	4.40	4.80	0.173	0.189
H1	2.50	2.90	0.098	0.114
L	14.50	16.50	0.571	0.650
L1	8.20	8.70	0.323	0.343
Q	8°		Typ. 0.181	
P	7.10	7.60	0.280	0.299
P1	7.40	8.20	0.291	0.323



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## **SUGGESTED SOLDER PAD LAYOUT**



**Unit :mm**

<b>PACKAGE</b>	<b>A</b>	<b>B</b>	<b>C</b>	<b>D</b>	<b>E</b>	<b>F</b>
<b>TO-263</b>	10.80	11.40	16.90	3.50	2.54	1.10